

# 2SD1269

## Silicon NPN epitaxial planar type

For power switching

Complementary to 2SB0944

### ■ Features

- Low collector-emitter saturation voltage  $V_{CE(sat)}$
- Satisfactory linearity of forward current transfer ratio  $h_{FE}$
- Large collector current  $I_C$
- Full-pack package which can be installed to the heat sink with one screw.

### ■ Absolute Maximum Ratings $T_C = 25^\circ\text{C}$

| Parameter                             | Symbol    | Rating                   | Unit             |
|---------------------------------------|-----------|--------------------------|------------------|
| Collector-base voltage (Emitter open) | $V_{CBO}$ | 130                      | V                |
| Collector-emitter voltage (Base open) | $V_{CEO}$ | 80                       | V                |
| Emitter-base voltage (Collector open) | $V_{EBO}$ | 7                        | V                |
| Collector current                     | $I_C$     | 4                        | A                |
| Peak collector current                | $I_{CP}$  | 8                        | A                |
| Collector power dissipation           | $P_C$     | 35                       | W                |
|                                       |           | $T_a = 25^\circ\text{C}$ |                  |
| Junction temperature                  | $T_j$     | 150                      | $^\circ\text{C}$ |
| Storage temperature                   | $T_{stg}$ | -55 to +150              | $^\circ\text{C}$ |

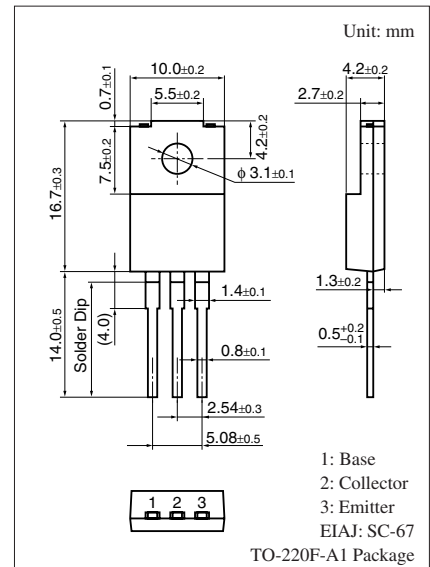
### ■ Electrical Characteristics $T_C = 25^\circ\text{C} \pm 3^\circ\text{C}$

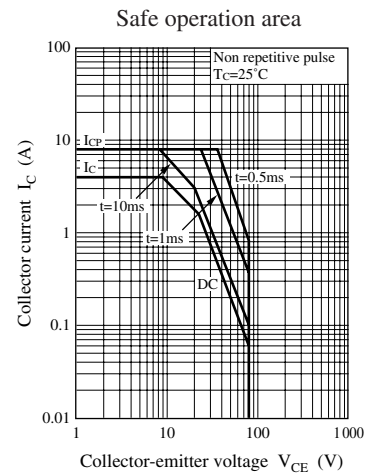
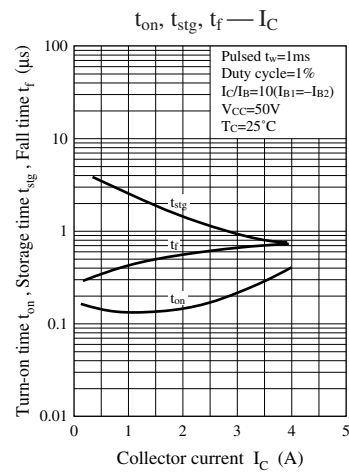
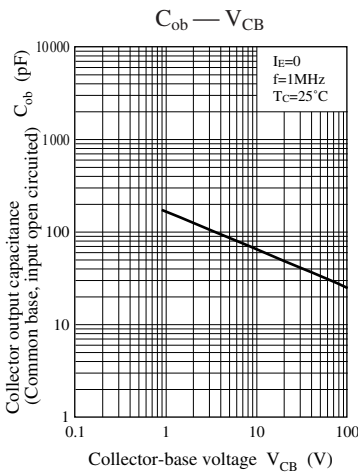
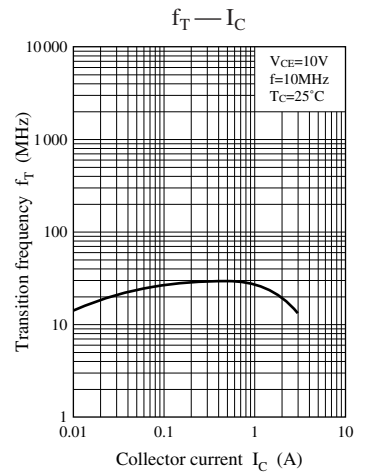
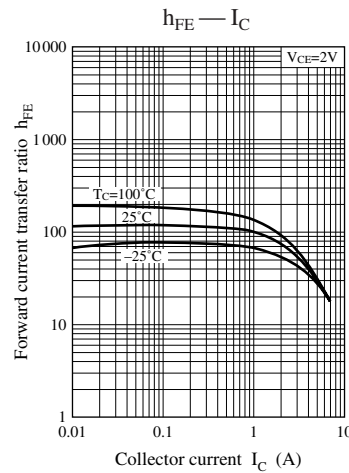
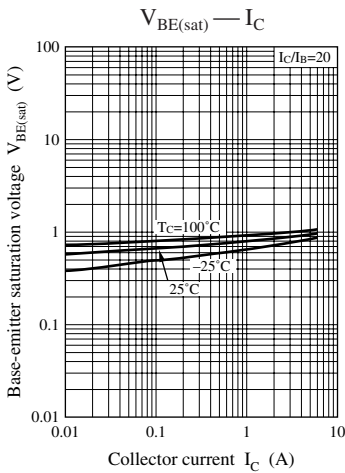
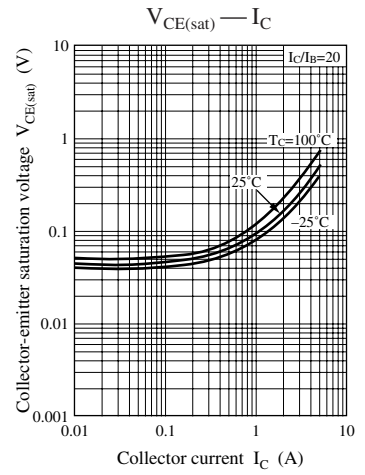
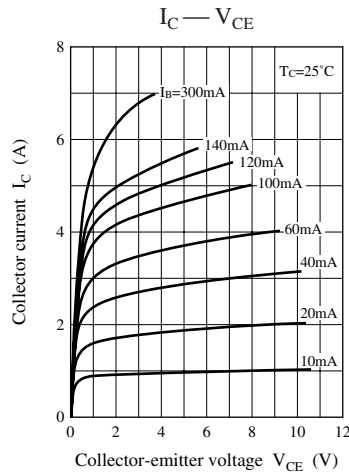
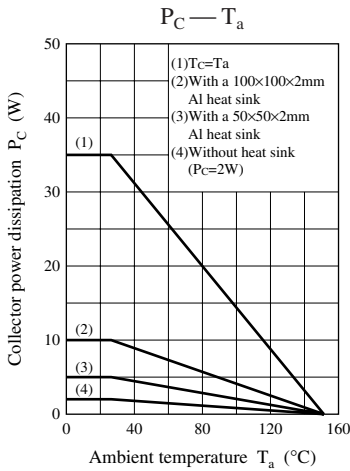
| Parameter                                     | Symbol        | Conditions  | Min | Typ  | Max | Unit          |
|---|---------------|---|-----|------|-----|---------------|
| Collector-emitter voltage (Base open)         | $V_{CEO}$     | $I_C = 10\text{ mA}, I_B = 0$                                     | 80  |      |     | V             |
| Collector-base cut-off current (Emitter open) | $I_{CBO}$     | $V_{CB} = 100\text{ V}, I_E = 0$                                  |     |      | 10  | $\mu\text{A}$ |
| Emitter-base cut-off current (Collector open) | $I_{EBO}$     | $V_{EB} = 5\text{ V}, I_C = 0$                                    |     |      | 50  | $\mu\text{A}$ |
| Forward current transfer ratio                | $h_{FE1}$     | $V_{CE} = 2\text{ V}, I_C = 0.1\text{ A}$                         | 45  |      |     | —             |
|   | $h_{FE2}^*$   | $V_{CE} = 2\text{ V}, I_C = 1\text{ A}$                           | 60  |      | 260 |               |
| Collector-emitter saturation voltage          | $V_{CE(sat)}$ | $I_C = 3\text{ A}, I_B = 0.15\text{ A}$                           |     |      | 0.5 | V             |
| Base-emitter saturation voltage               | $V_{BE(sat)}$ | $I_C = 3\text{ A}, I_B = 0.15\text{ A}$                           |     |      | 1.5 | V             |
| Transition frequency                          | $f_T$         | $V_{CE} = 10\text{ V}, I_C = 0.5\text{ A}, f = 10\text{ MHz}$     |     | 30   |     | MHz           |
| Turn-on time                                  | $t_{on}$      | $I_C = 1\text{ A}, I_{B1} = 0.1\text{ A}, I_{B2} = -0.1\text{ A}$ |     | 0.5  |     | $\mu\text{s}$ |
| Storage time                                  | $t_{stg}$     | $V_{CC} = 50\text{ V}$  |     | 2.5  |     | $\mu\text{s}$ |
| Fall time                                     | $t_f$         |   |     | 0.15 |     | $\mu\text{s}$ |

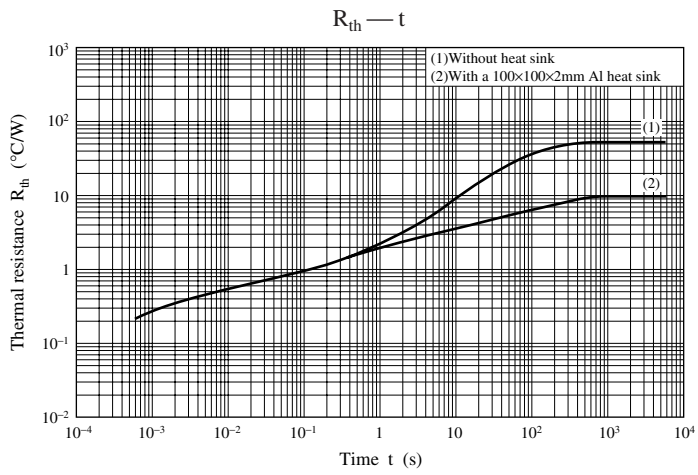
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*: Rank classification

| Rank      | R         | Q         | P          |
|-----------|-----------|-----------|------------|
| $h_{FE2}$ | 60 to 120 | 90 to 180 | 130 to 260 |







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